

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 129219		APPLICATION NO. 10/590,973	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Ali LAAYOUN et al.			
				FILING DATE August 28, 2006		GROUP 1626	
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EXAMINER					DATE CONSIDERED		
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Date: December 31, 2009

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /M.B./

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EXAMINER		/Michael Barker/				DATE CONSIDERED 01/04/2010	
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